

Amendments To The Claims

The following listing of claims will replace all prior versions and listings of claims in the application:

Listing of Claims:

Claims 1-26 (**canceled**)

Claim 27 (**currently amended**): A device comprising:

a substrate;
a lanthanum nickel ~~oxide oxide~~ (LaNiO₃) layer formed over the substrate, said lanthanum nickel oxide layer having a non-amorphous microstructure that comprises grains of crystalline material, the grains having an average diameter in the range from 100 Å to 300 Å; and
a layer of ferro-electric material formed over said lanthanum nickel oxide layer.

Claim 28 (**canceled**).

Claim 29 (**currently amended**): The device of Claim 27 wherein the lanthanum nickel ~~oxide oxide~~ layer has an average surface roughness in a range from 2 nm to 3 nm.

Claim 30 (**currently amended**): The device of Claim 27 wherein the lanthanum nickel ~~oxide oxide~~ layer has a resistivity of less than 330 μΩ·cm.

Claim 31 (**currently amended**): The device of Claim 27 wherein the lanthanum nickel ~~oxide oxide~~ layer has a resistivity of less than 300 μΩ·cm.

Claim 32 (**currently amended**): The device of Claim 27 wherein the lanthanum nickel ~~oxide oxide~~ layer has a resistivity of less than 250 μΩ·cm.

Claim 33 (**New**): The device of Claim 27 wherein the grains of the crystalline material of the lanthanum nickel oxide layer have a crystal lattice constant that is closely matched to the crystal lattice constant of the substrate.